

REFERENCES

- [1] DIETER K. SCHRODER, “SEMICONDUCTOR MATERIAL AND DEVICE CHARACTERIZATION”, A Wiley-Interscience Publication, USA, 2006.
- [2] A. TREATISE, “SEMICONDUCTORS AND SEMIMETALS”, Volume 21, Part C, Academic Press Inc., Orlando, Florida,USA, 1984.
- [3] [SIMON M. SZE](#), [KWOK K. NG](#), “PHYSICS OF SEMICONDUCTOR DEVICES”, 3rd Edition, John Wiley & Sons, Inc. 2007.
- [4] C. KITTEL, “PHYSIQUE DE L’ETAT SOLIDE”, Edition Dunod, Paris, France, 1998.
- [5] T. TIBERMACHINE, “CARACTERISATION DES DEFAUTS PROFONDS DANS LE SILICIUM AMORPHE HYDROGENE ET AUTRES SEMICONDUCTEURS PHOTO-ACTIFS DE TYPE III-V PAR LA METHODE DE PHOTOCOURANT CONSTANT: CPM”, Thèse de Doctorat, Université Biskra, 2011.
- [6] R. A. STREET, “HYDROGENATED AMORPHOUS SILICON”, Cambridge university press, 1991.
- [7] M. F. THORPE AND L. TICHY, “PROPERTIES AND APPLICATIONS OF AMORPHOUS MATERIALS”, Proceedings of NATO Advanced Study Institute, Czech Republic, 25 June-7 July 2000.